
Windows 7 Professional 64 bits (Chinese)

Windows XP Pinyin Windows 7 Simplified Chinese Keyboard A: First you have to change the input method used to be the pinyin IME, here is how you do it in Win 7 or Win 8. First launch Microsoft Input Language Assistant (MSIALC.exe) On the left pane, select "Input Method" and there will be an option named "Microsoft Pinyin" Click on the checkbox "Use this input method to interact with Simplified Chinese text" Click "OK" In the following step you have to know that the input method in Simplified Chinese is based on phonetics and not spelling. Go to the Main Keyboard and click on the icon of Keyboard Tools Make sure that the Chinese Simplified input method is in the list Now you are ready to go. PS, You can configure this input method to use some characters to put in the "Jump to Input Method" box. You can choose for example "zh-Hans" and then type "Zh" and you will be directed to the Chinese Simplified input method. (I am not sure it will work on Win 8 though). The present disclosure relates to a semiconductor device including a fuse, and more particularly to a semiconductor device including a fuse that can be blown by light. Generally, a semiconductor device may perform a desired operation using various test patterns by applying a test pattern to a semiconductor wafer during the fabricating process. After the wafer is subjected to the process, the semiconductor device may be subjected to a burn-in test and an electrical test. The electrical test is performed by inputting a current in order to ensure reliability of the semiconductor device, by applying a stress on the device to detect a defect, and the like. In this case, the semiconductor device may include several test pads configured to apply a test pattern or a stress to the semiconductor device. Accordingly, a scan chain method is used in order to test one device at a time. In the scan chain method, a plurality of test pads are alternately selected, and sequentially connected to a selected test pad in order to apply the test pattern to the semiconductor device. However, as the number of test pads increases, the test time increases and thus a test time per lot decreases.— A North Carolina man was arrested on multiple drug charges after he led police on an almost 40-minute chase on North



